


<b>Search Notes</b>  	<b>Application/Control No.</b>  10540283	<b>Applicant(s)/Patent Under Reexamination</b>  DUFFY ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN Structure	8/9/2007	sl
PALM Inventor Search (all inventors)	8/9/2007	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner